

(19) World Intellectual Property
Organization
International Bureau



(43) International Publication Date
3 March 2005 (03.03.2005)

PCT

(10) International Publication Number
WO 2005/019938 A1

(51) International Patent Classification⁷: **G03F 7/20**,
9/00, 1/14

(21) International Application Number:
PCT/IB2004/051568

(22) International Filing Date: 26 August 2004 (26.08.2004)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:
60/497,960 26 August 2003 (26.08.2003) US

(71) Applicant (for all designated States except US): **KONINKLIJKE PHILIPS ELECTRONICS, N.V.** [NL/NL];
Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).

(72) Inventor; and

(75) Inventor/Applicant (for US only): **AMATO, Joseph M.**
[US/US]; 1109 McKay Drive, M/S-SJ41, San Jose, CA
95131-1706 (US).

(74) Common Representative: **KONINKLIJKE PHILIPS ELECTRONICS, N.V.**; c/o Shannon Lester, 1109 McKay
Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).

(81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

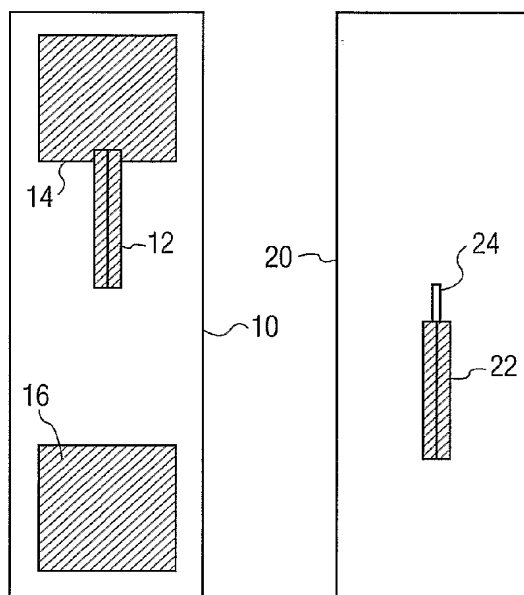
(84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Declarations under Rule 4.17:

— as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ,

[Continued on next page]

(54) Title: PROPORTIONAL VARIABLE RESISTOR STRUCTURES TO ELECTRICALLY MEASURE MASK MISALIGNMENT



(57) Abstract: A system, method and structures employing proportional variable resistors suitable for electrically measuring unidirectional misalignment of stitched masks in etched interconnect layers. In an example embodiment, there is a structure (10, 20) that comprises at least one proportional variable resistor (24) suitable for electrically measuring unidirectional misalignment of stitched masks in etched interconnect layers. The structure (10,20) comprises at least a first mask (10) and a second mask (20) that when superimposed comprise at least two test pads (14, 16) and interconnects (12, 22) the resistance between (24) which can be measured.

WO 2005/019938 A1



CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW, ARIPO patent (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG)

— as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(iii)) for all designations

Published:

- with international search report
- before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.